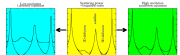


Sensors for XPAD hybrid pixel detectors : Si (5-25keV), CdTe (8-40keV).

Exploration of reciprocal space, profile shape, diffuse scattering...
The Fourier transform of the image is widely spreading...



- resolution optimized during experiment by adjusting detector position
- pixel size \approx beam spot size \approx 150 μ m
- detector has to be mounted on goniometer arm \rightarrow mass, convection

XPAD project (BIM2DRESRF, CPPM-IN2P3, NEEL-CNRS, SOLEIL)
Barar, JSR 2001, Boudet NIM-B 2004, Basolo IEEE-TNS 2005

Principe : associer une chaîne électronique complète à chaque pixel



- The XPAD project (XPAD1-2)
 - \rightarrow 24 pixels/circuit
 - Circuits: AMS CMOS
 - 0.8 μ m
 - Die area: 300 μ m²
- dynamic range $>$ 10⁷ count/pixel
- saturation rate $>$ 10⁷ V/pixel
- energy range 5 - 25 keV
- pixel size 330 x 330 μ m²
- exposure time 1ms - 100s
- \rightarrow 32 bits architecture
- \rightarrow noise $<$ 0.1 e⁻/pixel
- from beamline energy range
- spot size (1905) \approx 250 x 400 μ m²
- kinetics polarity

New diodes of 500 μ m Si stick \rightarrow efficiency 78 % @15keV, 21% @25keV

- Diode = 8 chips of 24 x 24 pixels
- PCB card : drivers and regulators.
- Module : acquisition card
- Altera Nexa kit = ethernet
- Tied as close as possible \rightarrow reduce shading, dead zones
- Metallic holder \rightarrow few μ m.
- Size : 200 x 192 pixels
- Surface : 68 x 68mm².
- Interface software developed using LabWindows/CVI application software moves to Linux.
- XPAD prototype on BM2D beamline.

J.-F. Bérar N. Boudet

February 6, 2008

Kinetics potentiality of XPAD2

XPAD2 whole electronic designed to allow kinetics studies (ms range).

- chips register 16bits + overflow
- on-board memories 32 bits
- exposure time : 1ms - 8000s
- dead time for reading :
 - whole image 2ms
 - overflow 10 μ s each 10ms
- on-board storage :
 - 423 images \approx 10ms
 - 233 images \approx 10ms



The quench of Al_2O_3 , Ca_2SiO_4 , ceramics can lead to vitrous or crystalline oxides. The transition between the liquid state and the crystalline one occurs in less than 20ms and may exhibit some transient phases.

Data collection is limited by the cell aperture, which has been designed for linear detector, diagram reconstructed from a few frames of 20ms

XPAD3 design

- Obsolescence of the AMS-CMOS 0.8 μ m technology
- New XPAD3 using 25 μ m technology with 25 μ m bumps
- New analog and digital architecture

| | XPAD2 | XPAD3S | XPAD3C |
|-----------------|--------------------------------|--|--|
| polarization | beam | beam | σ^* (CEITE) |
| pixel size | 330 x 330 μ m ² | 130 x 130 μ m ² | 130 x 130 μ m ² |
| chip size | 8 x 10 mm ² | 10 x 15 mm ² | 10 x 15 mm ² |
| frequency | 5.10 ⁷ Hz | 5.10 ⁷ Hz (= count/surface) | 5.10 ⁷ Hz (= count/surface) |
| photons rate | 2.10 ¹⁰ ph/s/pixel | 2.10 ¹⁰ ph/s/pixel | low level (low count/surface) |
| counters (bits) | 16 + 16 ext | 12 = 16 ext (= count/surface) | 12 = 16 ext (= count/surface) |
| energy range | (5) 15 - 25keV | 5 - 32keV | 7 - 60keV |
| energy edges | low level | low level | low and up levels |
| pixels/chip | 24 x 25 = 600 | 80 x 120 = 110 | 80 x 120 = 110 |
| pixels/module | 8 x 600 = 5.10 ³ | \approx 7.10 ³ | \approx 7.10 ³ |
| pixels/detector | \approx 4.10 ⁴ | \approx 5.10 ⁴ | \approx 5.10 ⁴ |
| geometries | 8 x 8 = 2 x 5 | 7 x 8 and ... | 7 x 8 and ... |

The chip layout and pixel chain in XPAD3S.

Power=40mW/pixel, electronic noise = 100e rms

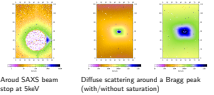
Time response of the preamplifier.

1500 transistors dans chaque pixel dont 1000 partie numérique et 500 partie analogique, soit environ 15 millions pour le circuit (le processeur Pentium III en techno 0.25um est content environ 9 millions).

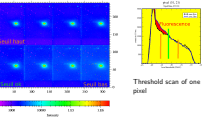
Pangaud et al., NIM A571 (2007) 321-324

XPAD3S with Si sensor

The assembly of a wide XPAD3S detector is not yet finished (Nov. 2007) as the first chips have been received in January. However, numerous tests have been carried out on small prototypes ... Results fulfilled the expected performances.

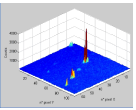


XPAD3S Si bounded Energy resolution, removing fluorescence



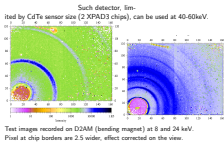
The quasycrystal scattering recorded at 16keV contains a continuous background due to Zn fluorescence. By shifting the common edge the fluorescence and then the signal itself are cutted (from bottom right to top left).

XPAD3S Si bounded at 5.9keV

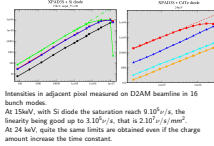


Preliminary tests have been conducted on SOLEIL at low energy (5.9keV). On left, diffraction peaks of a lysozyme crystal observed while rotation the crystal by 0.05 deg. steps.

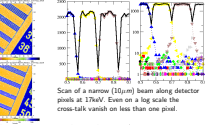
XPAD3S CdTe bounded : high energy becomes available



XPAD3S Si and CdTe hybridised : counting linearity

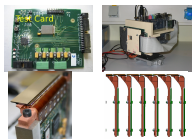


XPAD3S spatial resolution using 500 μ m Si sensor.

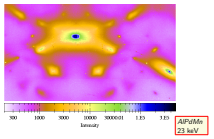


The image test measure about 40 lines pair / mm using a non perfect instrumental settings (source size 0.3mm at 270mm and detector at \approx 15 mm of test chart.

From chips to modules



XPAD3S Si modules 1st images



XPAD Collaboration

Thanks to all participants

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¹ D2AM/ESRF ² Inst. NEEL ³ CPPM-IN2P3 ⁴ Sync. SOLEIL ⁵ SOLEIL

Grenoble Marseille St Aubin

and for your attention!